

V _{DSS}	-20V
R _{DS(on)} (Max.)	105mΩ
I _D	±2.4A
P _D	1.25W

Features

- 1) Pch MOSFET and shottky barrier diode are put in TSST8 package.
- 2) High-speed switching and Low onresistance.
- 3) Low voltage drive(1.5V)
- 4) Built in Low I_R shottky barrier diode.



Inner circuit



•Packaging specifications

	Packing	Embossed Tape
	Reel size (mm)	180
Туре	Tape width (mm)	8
	Basic ordering unit (pcs)	3000
	Taping code	TR
	Marking	U02

Application

Switching

• Absolute maximum ratings ($T_a = 25^{\circ}C$)

< MOSFET >

Parameter	Symbol	Value	Unit
Drain - Source voltage	V _{DSS}	-20	V
Gate - Source voltage	V _{GSS}	±10	V
Continuous drain current	I _D	±2.4	A
Pulsed drain current	L _{D, pulse} *1	±9.6	A
Continuous source current (body diode)	IS	-0.8	A
Pulsed source current (body diode)	I _{S, pulse} *1	-9.6	A
Power dissipation	P _D *2	1.0	W/element
Junction temperature	Tj	150	°C

• Absolute maximum ratings ($T_a = 25^{\circ}C$)

< Diode >

Parameter	Symbol	Value	Unit
Repetitive peak reverse voltage	V _{RM}	30	V
Reverse voltage	V _R	20	V
Forward current	I _F	1.0	A
Forward current surge peak	I _{FSM} *3	3.0	A
Power dissipation	P _D ^{*2}	1.0	W/element
Junction temperature	Tj	150	°C

< MOSFET + Diode >

Parameter	Symbol	Value	Unit
Power dissipation	P _D *2	1.25	W/total
Range of storage temperature	T _{stg}	-55 to +150	°C

• Electrical characteristics (T_a = 25°C)

< MOSFET >

Deremeter	Current of	Conditions		Values		l lait
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Gate - Source leakage current	GSS	V_{GS} = ±10V, V_{DS} = 0V	-	-	±100	nA
Drain - Source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -1mA	-20	-	-	V
Zero gate voltage drain current	I _{DSS}	V _{DS} = -20V, V _{GS} = 0V	-	-	-1	μA
Gate threshold voltage	$V_{GS(th)}$	V _{DS} = -10V, I _D = -1mA	-0.3	-	-1.0	V
		V _{GS} = -4.5V, I _D = -2.4A	-	80	105	
Static drain - source	D *4	V _{GS} = -2.5V, I _D = -1.2A	-	105	140	
on - state resistance	$R_{DS(on)}^{*4}$	V _{GS} = -1.8V, I _D = -1.2A	-	150	225	mΩ
		V _{GS} = -1.5V, I _D = -0.5A	-	180	360	
Forward Transfer Admittance	Y _{fs} ^{∗4}	V _{DS} = -10V, I _D = -2.4A	2.4	-	-	S

• Electrical characteristics (T_a = 25°C)

< MOSFET >

Deremeter	Sumbol	Conditions		Values		Unit
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Input capacitance	C _{iss}	V _{GS} = 0V	-	850	-	
Output capacitance	C _{oss}	V _{DS} = -10V	-	60	-	pF
Reverse transfer capacitance	C _{rss}	f = 1MHz	-	50	-	
Turn - on delay time	t _{d(on)} *⁴	V _{DD} ≃ -10V, V _{GS} = -4.5V	-	9	-	
Rise time	t _r *4	I _D = -1.2A	-	25	-	20
Turn - off delay time	$t_{d(off)}^{*4}$	R _L = 8.3Ω	_	55	-	ns
Fall time	t_{f}^{*4}	R _G = 10Ω	-	45	-	

• Gate charge characteristics ($T_a = 25^{\circ}C$)

< MOSFET >

Deremeter	Symbol	Conditions		Values		Unit
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Total gate charge	Q_g^{*4}		-	6.7	-	
Gate - Source charge	Q _{gs} *4	V _{DD} ≃ -10V, I _D = -2.4A V _{GS} = -4.5V	-	1.7	-	nC
Gate - Drain charge	${\sf Q}_{\sf gd}{}^{*4}$		-	0.6	-	

•Body diode electrical characteristics (Source-Drain) (T_a = 25°C)

< MOSFET >

Peremeter	Symbol	Conditions	Values		Max. Unit	
Parameter		Min.	Тур.	Max.	Unit	
Forward voltage	V_{SD}^{*4}	V _{GS} = 0V, I _S = -2.4A	-	-	-1.2	V



• Electrical characteristics (T_a = 25°C)

< Diode >

Deremeter	Sumbol	Conditions		Values		Unit
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Forward voltage	V_{F}	I _F = 1.0A	-	0 <u>.</u> 48	0.52	V
Reverse current	I _R	V _R = 10V	-	-	10	μA

*1 Pw \leq 0µs, Duty cycle \leq 1%

*2 MOUNTED ON A CERAMIC BOARD (30×30×0.8mm)

*3 60Hz 1cycle

*4 Pulsed





Electrical characteristic curves <MOSFET>

Fig.1 Typical Output Characteristics(I)

Fig.2 Typical Output Characteristics(II)



5/12

20150731 - Rev.001

ROHM

• Electrical characteristic curves < MOSFET >



6/12



Electrical characteristic curves <MOSFET>





7/12

ROHM





8/12



ROHM



•Electrical characteristic curves <MOSFET>



9/12



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• Electrical characteristic curves <Di>





Measurement circuits



Notice

- SBD has a large reverse leak current compared to other type of diode. Therefore, it would raise a junction temperature, and increase a reverse power loss. Further rise of inside temperature would cause a thermal runaway. This built-in SBD has low V_F characteristics and therefore, higher leak current. Please consider enough the surrounding temperature, generating heat of MOSFET and the reverse current.
- 2. This product might cause chip aging and breakdown under the large electrified environment. Please consider to design ESD protection circuit.





Dimensions

TSST8



Pattern of terminal position areas [Not a pattern of soldering pads]

DIM	MILIM	ETERS	INC	HES	
	MIN	MAX	MIN	MAX	
Α	0.75	0.85	0.030	0.033	
A1	0.00	0.05	0.000	0.002	
b	0.22	0.42	0.009	0.017	
С	0.12	0.22	0.005	0.009	
D	2.90	3.10	0.114	0.122	
E	1.50	1.70	0.059	0.067	
е	0.	65	0.026		
HE	1.80	2.00	0.071	0.079	
L	0.05	0.25	0.002	0.010	
L1	0.05	0.25	0.002	0.010	
Lp	0.15	0.34	0.006	0.013	
Lp1	0.15	0.34	0.006	0.013	
x	-	0.10	-	0.004	
У	S 	0.10	-	0.004	

DIM	MILIM	ETERS	INC	HES
	MIN	MAX	MIN	MAX
b2	(-	0.52	-	0.020
e1	1.	1.46)57
11	<u>81</u>	0.44	<u>a</u>	0.017
12	83 	0.44	-	0.017

Dimension in mm/inches







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